







SN75HVD08, SN65HVD08

SLLS550E - NOVEMBER 2002 - REVISED MARCH 2023

SNx5HVD08 Wide Supply Range RS-485 Transceiver

1 Features

- Operates with a 3-V to 5.5-V supply
- Consumes less than 90-mW Quiescent power
- Open-circuit, short-circuit, and idle-bus failsafe receiver
- 1/8th Unit-load (up to 256 nodes on the bus)
- Bus-pin ESD protection exceeds 16-kV HBM
- Driver output voltage slew-rate limited for optimum signal quality at 10 Mbps
- Electrically compatible with ANSI TIA/EIA-485

2 Applications

- Data transmission with remote stations powered from the host
- Isolated multipoint data buses
- Industrial process control networks
- Point-of-sale networks
- Electric utility metering

3 Description

The SN65HVD08 combines a 3-state differential line driver and differential line receiver designed for balanced data transmission and interoperation with ANSI TIA/EIA-485-A and ISO-8482E standardcompliant devices.

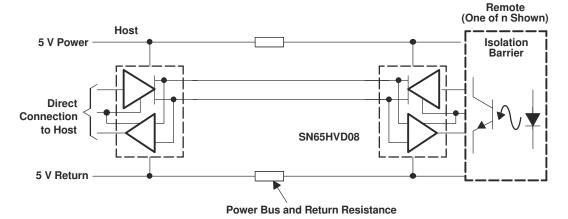
The wide supply voltage range and low quiescent current requirements allow the SN65HVD08s to operate from a 5-V power bus in the cable with as much as a 2-V line voltage drop. Busing power in the cable can alleviate the need for isolated power to be generated at each connection of a ground-isolated

The driver differential outputs and receiver differential inputs connect internally to form a differential input/ output (I/O) bus port that is designed to offer minimum loading to the bus whenever the driver is disabled or not powered. The drivers and receivers have activehigh and active-low enables respectively, which can be externally connected together to function as a direction control.

Package Information

PART NUMBER	PACKAGE ⁽¹⁾	BODY SIZE (NOM)
SN75HVD08,	SOIC (8)	4.90 mm × 3.91 mm
SN65HVD08	PDIP (8)	9.81 mm × 6.35 mm

For all available packages, see the orderable addendum at the end of the datasheet.



Typical Application Schematic



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4 Revision History Changes from Revision D (March 2015) to Revision	F (February 2023)	Page
Changed the <i>Thermal Information</i> table		
Changed the Typical Characteristics		
- Onlanged the Typical Characteristics		
Changes from Revision C (July 2006) to Revision D	(March 2015)	Page
 Added Pin Configuration and Functions section, ES Functional Modes, Application and Implementation section, Device and Documentation Support section 	section, Power Supply Recommendations section	on, <i>Layout</i>

section ______1

5 Pin Configuration and Functions

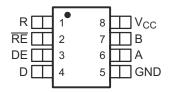


Figure 5-1. D or P Package, 8-Pin SOIC or PDIP (Top View)

Table 5-1. Pin Functions

P	IN	TYPE	DESCRIPTION
NAME	NO.	ITPE	DESCRIPTION
А	6	Bus input / output	Driver output and receiver input (complementary to B)
В	7	Bus input / output	Driver output and receiver input (complementary to A)
D	4	Digital input	Driver data input
DE	3	Digital input	Driver enable high
GND	5	Reference potential	Local device ground
R	1	Digital output	Receive data output
RE	2	Digital input	Receiver enable low
V _{CC}	8	Supply	3-V to 5.5-V supply

6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range unless otherwise noted(1) (2)

	MIN	MAX	UNIT
Supply voltage, V _{CC}	-0.3	6	V
Voltage at A or B	-9	14	V
Input voltage at D, DE, R or RE	-0.5	V _{CC} + 0.5	V
Voltage input, transient pulse, A and B, through 100 Ω	-25	25	V
Receiver output current, I _O	-11	11	mA
Maximum Junction Temperature, T _J		150	°C
Storage Temperature, T _{STG}	-65	150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

				VALUE	UNIT
V _(ESD) Electrostatic discharge		riaman body model (ribiti), per Altoneobaroebeo	A, B, and GND	16000	
	JS-001 ⁽¹⁾	All pins	4000	V	
		Charged-device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾		1000	

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

⁽²⁾ All voltage values, except differential I/O bus voltages, are with respect to network ground terminal.

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



6.3 Recommended Operating Conditions

		MIN	NOM N	IAX	UNIT
Supply voltage, V _{CC}		3		5.5	V
Input voltage at any bus terminal (se	eparately or common mode), V _I ⁽¹⁾	-7		12	V
High-level input voltage, V _{IH}		2.25		V _{CC}	V
Low-level input voltage, V _{IL}	Driver, driver enable, and receiver enable inputs			8.0	V
Differential input voltage, V _{ID}		-12		12	
High level output ourrent I	Driver	-60			mA
High-level output current, I _{OH}	Receiver	-8			
Low level output ourrent I	Driver			60	A
Low-level output current, I _{OL}	Receiver			8	mA
Operating free air temperature T	SN75HVD08	0		70	°C
Operating free-air temperature, T _A	SN65HVD08	-40		85	°C

⁽¹⁾ The algebraic convention, in which the least positive (most negative) limit is designated as minimum is used in this data sheet.

6.4 Thermal Information

	THERMAL METRIC ⁽¹⁾	D (SOIC) SN75 Version	D (SOIC) SN65 Version	P (PDIP)	UNIT
		8 PINS	8 PINS	8 PINS	
R _{0JA}	Junction-to-ambient thermal resistance	175.4	116.7	125	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	53.6	56.3	34.9	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	45.1	63.4	23.7	°C/W
Ψ _{JT}	Junction-to-top characterization parameter	10.1	8.8	12.1	°C/W
ΨЈВ	Junction-to-board characterization parameter	44.4	62.6	23.6	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report, SPRA953.

6.5 Electrical Characteristics

over recommended operating conditions unless otherwise noted

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V _{OD}	Driver differential output voltage magnitude	R_L = 60 Ω, 375 Ω on each output to -7 V to 12 V, See Figure 7-1	1.5		V _{CC}	V
Δ V _{OD}	Change in magnitude of driver differential output voltage	R _L = 54 Ω	-0.2		0.2	V
V _{OC(PP)}	Peak-to-peak driver common-mode output voltage	Center of two 27-Ω load resistors, See Figure 7-2		0.5		V
V _{IT+}	Positive-going receiver differential input voltage threshold				-10	mV
V _{IT-}	Negative-going receiver differential input voltage threshold		-200			mV
V _{hys}	Receiver differential input voltage threshold hysteresis(V _{IT+} - V _{IT-})			35		mV
V _{OH}	Receiver high-level output voltage	I _{OH} = -8 mA	2.4			V
V _{OL}	Receiver low-level output voltage	I _{OL} = 8 mA			0.4	V
I _{IH}	Driver input, driver enable, and receiver enable high-level input current		-100		100	μΑ
I _{IL}	Driver input, driver enable, and receiver enable low-level input current		-100		100	μA
I _{OS}	Driver short-circuit output current	7 V < V _O < 12 V	-265		265	mA



6.5 Electrical Characteristics (continued)

over recommended operating conditions unless otherwise noted

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
		V _I = 12 V			130		
١,	Pue input current (disabled driver)	V _I = -7 V	-100				
11	Bus input current (disabled driver)	V _I = 12 V, V _{CC} = 0 V			130	μA	
		V _I = -7 V. V _{CC} = 0 V	-100				
		Receiver enabled, driver disabled, no load			10	mA	
I _{cc}	Supply current	Driver enabled, receiver disabled, no load			16	IIIA	
		Both disabled			5	μA	
		Both enabled, no load			16	mA	

6.6 Driver Switching Characteristics

over recommended operating conditions unless otherwise noted

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PHL}	Driver high-to-low propagation delay time		18		40	
t _{PLH}	Driver low-to-high propagation delay time		18		40	
t _r	Driver 10%-to-90% differential output rise time	R_L = 54 Ω , C_L = 50 pF,See Figure 7-3	10		55	ns
t _f	Driver 90%-to-10% differential output fall time		10		55	
t _{SK(P)}	Driver differential output pulse skew, t _{PHL} - t _{PLH}				2.5	
	Driver enable time	Receiver enabled, See Figures 4 and 5			55	ns
l _{en}	Driver enable time	Receiver disabled, See Figures 4 and 5			6	μs
t _{dis}	Driver disable time	Receiver enabled, See Figures 4 and 5			90	ns

6.7 Receiver Switching Characteristics

over recommended operating conditions unless otherwise noted

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PHL}	Receiver high-to-low propagation delay time				70	
t _{PLH}	Receiver low-to-high propagation delay time				70	
t _r	Receiver 10%-to-90% differential output rise time	C _L = 15 pF, See Figure 7-6			5	ns
t _f	Receiver 90%-to-10% differential output fall time				5	
t _{SK(P)}	Receiver differential output pulse skew, t _{PHL} - t _{PLH}				4.5	
	Receiver enable time	Driver enabled, See Figure 7-7			15	ns
^L en		Driver disabled, See Figure 7-8			6	μs
t _{dis}	Receiver disable time	Driver enabled, See Figure 7-7			20	ns



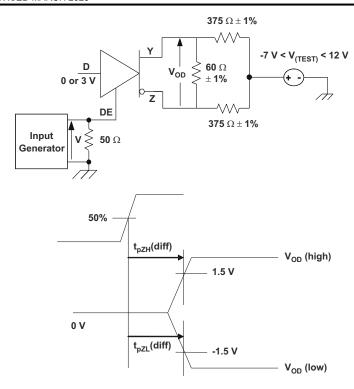
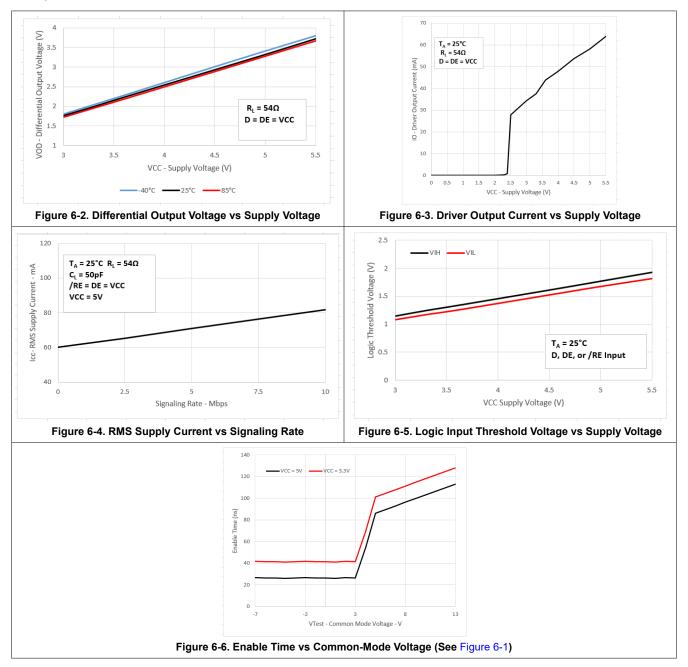


Figure 6-1. Driver Enable Time From DE to V_{OD}

The time $t_{pZL}(x)$ is the measure from DE to $V_{OD}(x)$. V_{OD} is valid when it is greater than 1.5 V.



6.8 Typical Characteristics





7 Parameter Measurement Information

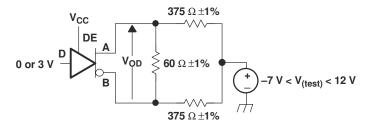
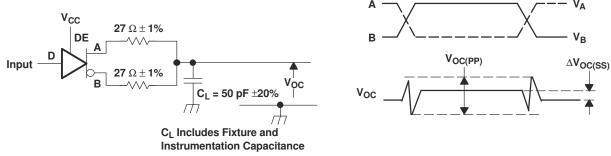
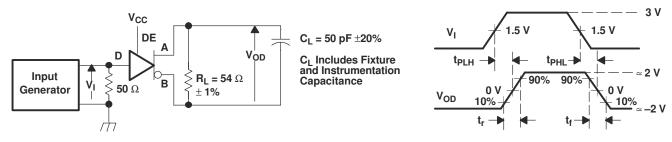


Figure 7-1. Driver V_{OD} With Common-Mode Loading Test Circuit



Input: PRR = 500 kHz, 50% Duty Cycle, t_r <6ns, t_f <6ns, Z_O = 50 Ω

Figure 7-2. Test Circuit and Definitions for the Driver Common-Mode Output Voltage



Generator: PRR = 500 kHz, 50% Duty Cycle, t_r <6 ns, t_f <6 ns, Z_o = 50 Ω

Figure 7-3. Driver Switching Test Circuit and Voltage Waveforms

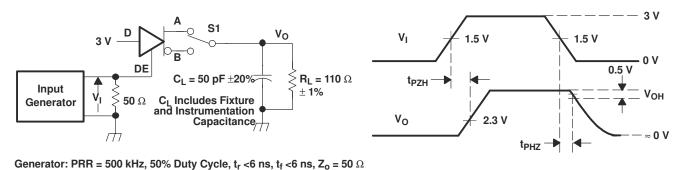
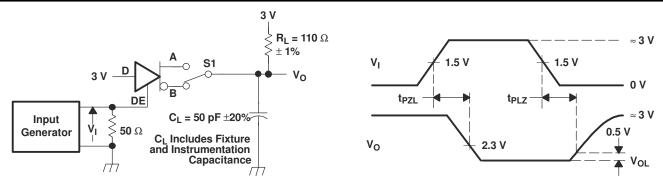


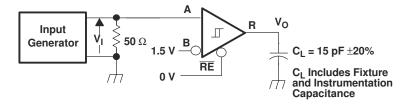
Figure 7-4. Driver High-Level Enable and Disable Time Test Circuit and Voltage Waveforms





Generator: PRR = 500 kHz, 50% Duty Cycle, t_r <6 ns, t_f <6 ns, Z_o = 50 Ω

Figure 7-5. Driver Low-Level Output Enable and Disable Time Test Circuit and Voltage Waveforms



Generator: PRR = 500 kHz, 50% Duty Cycle, t_{r} <6 ns, t_{f} <6 ns, Z_{o} = 50 Ω

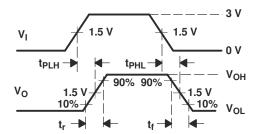
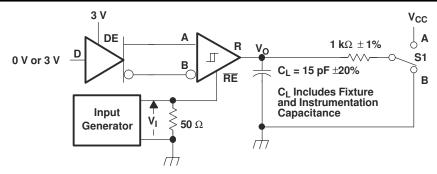


Figure 7-6. Receiver Switching Test Circuit and Voltage Waveforms





Generator: PRR = 500 kHz, 50% Duty Cycle, t_r <6 ns, t_f <6 ns, Z_o = 50 Ω

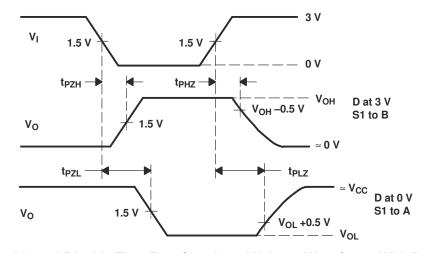
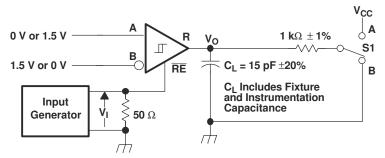


Figure 7-7. Receiver Enable and Disable Time Test Circuit and Voltage Waveforms With Drivers Enabled





Generator: PRR = 100 kHz, 50% Duty Cycle, t_r <6 ns, t_f <6 ns, Z_o = 50 Ω

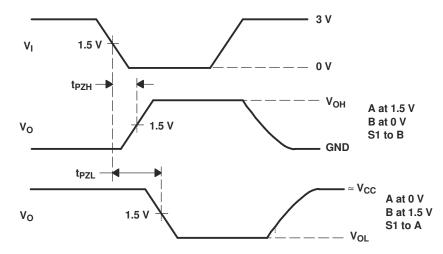


Figure 7-8. Receiver Enable Time From Standby (Driver Disabled)



8 Detailed Description

8.1 Overview

The SNx5HVD08 is a 3-V to 5.5-V, half-duplex, RS-485 transceiver suitable for data transmission up to 10 Mbps.

This device has an active-high driver enable and active-low receiver enable. A standby current of less than 5 μ A can be achieved by disabling both driver and receiver.

Device operation is specified over a wide temperature range from -40°C to +85°C.

8.2 Functional Block Diagram

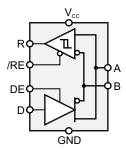


Figure 8-1. Logic Diagram (Positive)

8.3 Feature Description

Internal ESD protection circuits protect the transceiver bus terminals against ±16 kV Human Body Model (HBM) electrostatic discharges and all other pins up to ±4 kV.

The SNx5HVD08 provides internal biasing of the receiver input thresholds for open-circuit, bus-idle, or short-circuit failsafe conditions, and a typical receiver hysteresis of 35 mV.

8.4 Device Functional Modes

Table 8-1. Function Table: Driver

INPU	T ENABLE	OUT	TPUTS			
D	DE	Α	В			
Н	Н	Н	L			
L	Н	L	Н			
X	L	Z	Z			
Oper	n H	Н	L			

Table 8-2. Function Table: Receiver

DIFFERENTIAL INPUTS	ENABLE ⁽¹⁾	OUTPUT ⁽¹⁾
$V_{ID} = V_A - V_B$	RE	R
V _{ID} ≤ -0.2 V	L	L
-0.2 V < V _{ID} < -0.01 V	L	?
-0.01 V ≤ V _{ID}	L	H
X	Н	Z
Open Circuit	L	H
Short Circuit	L	Н

(1) H = high level; L = low level; Z = high impedance; X = irrelevant;? = indeterminate



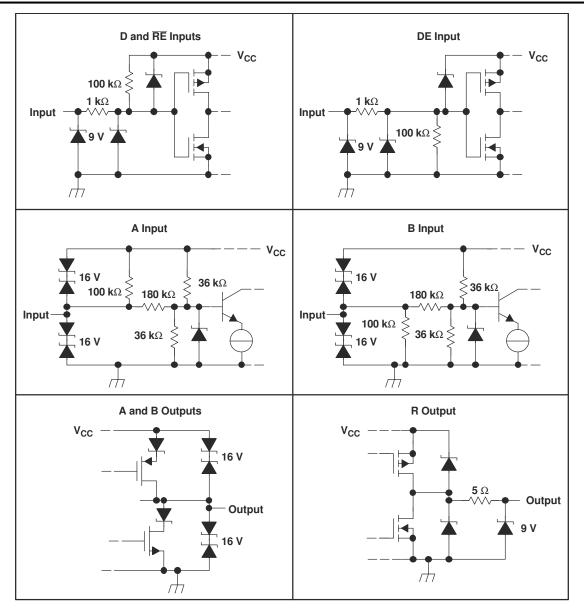


Figure 8-2. Equivalent Input and Output Schematic Diagrams

9 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

9.1 Application Information

As electrical loads are physically distanced from their power source, the effects of supply and return line impedance and the resultant voltage drop must be accounted. If the supply regulation at the load cannot be maintained to the circuit requirements, it forces the use of remote sensing, additional regulation at the load, bigger or shorter cables, or a combination of these. The SN65HVD08 eases this problem by relaxing the supply requirements to allow for more variation in the supply voltage over typical RS-485 transceivers.

9.1.1 Supply Source Impedance

In the steady state, the voltage drop from the source to the load is simply the wire resistance times the load current as modeled in Figure 9-1.

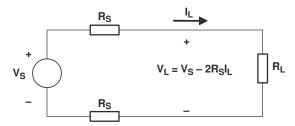


Figure 9-1. Steady-State Circuit Model

For example, if you were to provide 5-V ±5% supply power to a remote circuit with a maximum load requirement of 0.1 A (one SN65HVD08), the voltage at the load would fall below the 4.5-V minimum of most 5-V circuits with as little as 5.8 m of 28-GA conductors. Table 9-1 summarizes wire resistance and the length for 4.5 V and 3 V at the load with 0.1 A of load current. The maximum lengths would scale linearly for higher or lower load currents.

Table 9-1. Maximum Cable Lengths for Minimum Load Voltages at 0.1 A Load

WIRE SIZE	RESISTANCE	4.5-V LENGTH AT 0.1 A	3-V LENGTH AT 0.1 A	
28 Gauge	0.213 Ω/m	41.1 m		
24 Gauge	0.079 Ω/m	15.8 m	110.7 m	
22 Gauge	0.054 Ω/m	23.1 m	162.0 m	
20 Gauge	0.034 Ω/m	36.8 m	257.3 m	
18 Gauge	0.021 Ω/m	0.021 Ω/m 59.5 m		

Under dynamic load requirements, the distributed inductance and capacitance of the power lines may not be ignored and decoupling capacitance at the load is required. The amount depends upon the magnitude and frequency of the load current change but, if only powering the SN65HVD08, a 0.1 μ F ceramic capacitor is usually sufficient.

9.1.2 Opto-Isolated Data Buses

Long RS-485 circuits can create large ground loops and pick up common-mode noise voltages in excess of the range tolerated by standard RS-485 circuits. A common remedy is to provide galvanic isolation of the data circuit from earth or local grounds.

Transformers, capacitors, or phototransistors most often provide isolation of the bus and the local node. Transformers and capacitors require changing signals to transfer the information over the isolation barrier and phototransistors (opto-isolators) can pass steady-state signals. Each of these methods incurs additional costs and complexity, the former in clock encoding and decoding of the data stream and the latter in requiring an isolated power supply.

Quite often, the cost of isolated power is repeated at each node connected to the bus as shown in Figure 9-2. The possibly lower-cost solution is to generate this supply once within the system and then distribute it along with the data line(s) as shown in Figure 9-3.

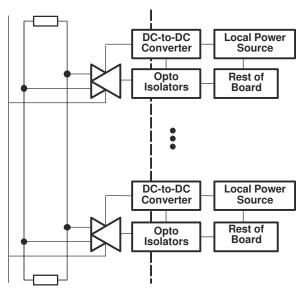


Figure 9-2. Isolated Power at Each Node

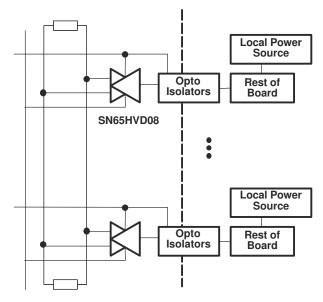


Figure 9-3. Distribution of Isolated Power

The features of the SN65HVD08 are particularly good for the application of Figure 9-3. Due to added supply source impedance, the low quiescent current requirements and wide supply voltage tolerance allow for the poorer load regulation.



9.1.3 Opto Alternative

The ISO150 is a two-channel, galvanically isolated data coupler capable of data rates of 80 Mbps. Each channel can be individually programmed to transmit data in either direction.

Data is transmitted across the isolation barrier by coupling complementary pulses through high-voltage 0.4-pF capacitors. Receiver circuitry restores the pulses to standard logic levels. Differential signal transmission rejects isolation-mode voltage transients up to 1.6 kV/ms.

ISO150 avoids the problems commonly associated with opto-couplers. Optically-isolated couplers require high current pulses and allowance must be made for LED aging. The ISO150's Bi-CMOS circuitry operates at 25 mW per channel with supply voltage range matching that of the SN65HVD08 of 3 V to 5.5 V.

Figure 9-4 shows a typical circuit.

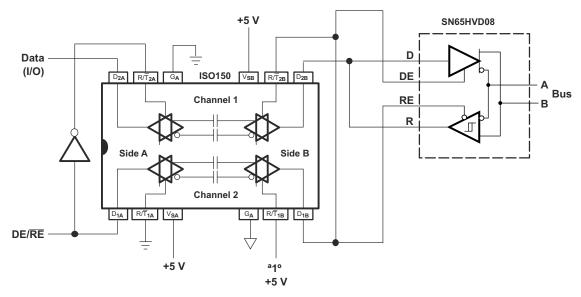


Figure 9-4. Isolated RS-485 Interface

9.2 Typical Application

An RS-485 bus consists of multiple transceivers connecting in parallel to a bus cable. To eliminate line reflections, each cable end is terminated with a termination resistor, R_T , whose value matches the characteristic impedance, Z_0 , of the cable. This method, known as parallel termination, allows for higher data rates over longer cable length.

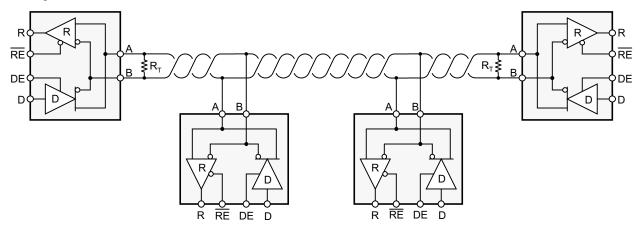


Figure 9-5. Typical Application Diagram

9.2.1 Design Requirements

RS-485 is a robust electrical standard suitable for long-distance networking that may be used in a wide range of applications with varying requirements, such as distance, data rate, and number of nodes.

9.2.1.1 Data Rate and Bus Length

There is an inverse relationship between data rate and bus length, meaning the higher the data rate, the shorter the cable length; and conversely, the lower the data rate, the longer the cable may be without introducing data errors. While most RS-485 systems use data rates between 10 kbps and 100 kbps, some applications require data rates up to 250 kbps at distances of 4000 feet and longer. Longer distances are possible by allowing for small signal jitter of up to 5 or 10%.

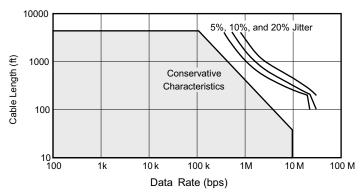


Figure 9-6. Cable Length vs Data Rate Characteristic



9.2.1.2 Stub Length

When connecting a node to the bus, the distance between the transceiver inputs and the cable trunk, known as the stub, should be as short as possible. Stubs present a non-terminated piece of bus line which can introduce reflections as the length of the stub increases. As a general guideline, the electrical length, or round-trip delay, of a stub should be less than one-tenth of the rise time of the driver, thus giving a maximum physical stub length as shown in Equation 1.

$$L_{\text{stub}} \le 0.1 \times t_{\text{r}} \times v \times c \tag{1}$$

Where:

- t_r is the 10/90 rise time of the driver
- c is the speed of light (3 × 10⁸ m/s)
- · v is the signal velocity of the cable or trace as a factor of c

Per Equation 1, the maximum recommended stub length for the minimum driver output rise time of the SNx5HVD08 for a signal velocity of 78% is 0.23 meters (0.75 feet).

9.2.1.3 Bus Loading

The RS-485 standard specifies that a compliant driver must be able to driver 32 unit loads (UL), where 1 unit load represents a load impedance of approximately 12 k Ω . Because the SN65HVD08 and SN75HVD08 are each 1/8 UL transceivers, it is possible to connect up to 256 receivers to the bus.

9.2.1.4 Receiver Failsafe

The differential receivers of the SNx5HVD08 family are "failsafe" to invalid bus states caused by:

- Open bus conditions, such as a disconnected connector
- · Shorted bus conditions, such as cable damage shorting the twisted-pair together
- · Idle bus conditions that occur when no driver on the bus is actively driving

In any of these cases, the differential receiver will output a failsafe logic High state so that the output of the receiver is not indeterminate.

Receiver failsafe is accomplished by offsetting the receiver thresholds such that the "input indeterminate" range does not include zero volts differential.

In order to comply with the RS-422 and RS-485 standards, the receiver output must output a High when the differential input VID is more positive than +200 mV, and must output a Low when VID is more negative than -200 mV. The receiver parameters which determine the failsafe performance are VIT(+) and VIT(-).

As shown in the Electrical Characteristics table, differential signals more negative than -200 mV will always cause a Low receiver output, and differential signals more positive than -10 mV will always cause a High receiver output. Thus, when the differential input signal is close to zero, it is still above the maximum VIT(+) threshold of -10 mV, and the receiver output will be High.

9.2.2 Detailed Design Procedure

In order to protect bus nodes against high-energy transients, the implementation of external transient protection devices is necessary.

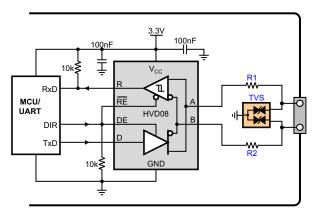


Figure 9-7. Transient protection against ESD, EFT, and Surge transients

Figure 9-7 suggests a protection circuit against 10 kV ESD (IEC 61000-4-2), 4 kV EFT (IEC 61000-4-4), and 1 kV surge (IEC 61000-4-5) transients. Table 9-2 shows the associated Bill of Materials.

Table 9-2. Bill of Materials

DEVICE	FUNCTION	ORDER NUMBER	MANUFACTURER
XCVR	3.3 V to 5 V, 10 Mbps RS-485 Transceiver	SNx5HVD08	TI
R1, R2	10 Ω, Pulse-Proof Thick-Film Resistor	CRCW0603010RJNEAHP	Vishay
TVS	Bidirectional 400 W Transient Suppressor	CDSOT23-SM712	Bourns

9.2.3 Application Curve

Figure 9-8 demonstrates operation of the SN65HVD08 at a signaling rate of 10 Mbps.

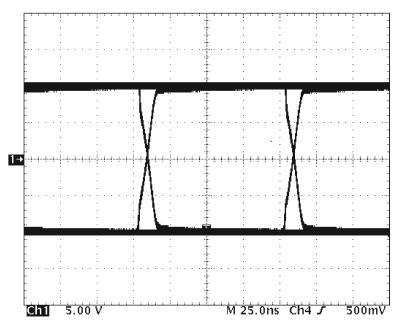


Figure 9-8. SNx5HVD08 Differential Output Waveform

9.3 Power Supply Recommendations

To ensure reliable operation at all data rates and supply voltages, each supply should be buffered with a 100-nF ceramic capacitor located as close to the supply pins as possible. The TPS76333 and TPS76350 are linear voltage regulators suitable for 3.3 V and 5 V supplies respectively.

9.4 Layout

9.4.1 Layout Guidelines

On-chip IEC-ESD protection is sufficient for laboratory and portable equipment but insufficient for EFT and surge transients occurring in industrial environments. Therefore, robust and reliable bus node design requires the use of external transient protection devices.

Because ESD and EFT transients have a wide frequency bandwidth from approximately 3 MHz to 3 GHz, high frequency layout techniques must be applied during PCB design.

- 1. Place the protection circuitry close to the bus connector to prevent noise transients from entering the board.
- 2. Use VCC and ground planes to provide low-inductance. Note that high-frequency currents follow the path of least inductance and not the path of least impedance.
- 3. Design the protection components into the direction of the signal path. Do not force the transient currents to divert from the signal path to reach the protection device.
- 4. Apply 100-nF to 220-nF bypass capacitors as close as possible to the VCC-pins of transceiver, UART, or controller ICs on the board.
- 5. Use at least two vias for VCC and ground connections of bypass capacitors and protection devices to minimize effective via-inductance.
- 6. Use 1-k Ω to 10-k Ω pullup and pulldown resistors for enable lines to limit noise currents in these lines during transient events.
- 7. Insert series pulse-proof resistors into the A and B bus lines if the TVS clamping voltage is higher than the specified maximum voltage of the transceiver bus terminals. These resistors limit the residual clamping current into the transceiver and prevent it from latching up.
- 8. While pure TVS protection is sufficient for surge transients up to 1 kV, higher transients require metal-oxide varistors (MOVs) which reduce the transients to a few hundred volts of clamping voltage, and transient blocking units (TBUs) that limit transient current to less than 1 mA.

9.4.2 Layout Example

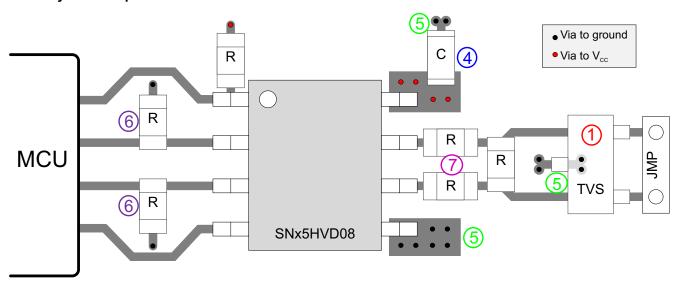


Figure 9-9. SNx5HVD08 Layout example



10 Device and Documentation Support

10.1 Device Support

10.1.1 Third-Party Products Disclaimer

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10.2 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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10.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

10.5 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
	(-)		J			(=)	(6)	(-)		()	
SN65HVD08D	NRND	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	VP08	
SN65HVD08DG4	NRND	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	VP08	
SN65HVD08DR	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	VP08	Samples
SN65HVD08DRG4	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	VP08	Samples
SN65HVD08P	ACTIVE	PDIP	Р	8	50	RoHS & Green	NIPDAU	N / A for Pkg Type	-40 to 85	65HVD08	Samples
SN75HVD08D	NRND	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	VN08	
SN75HVD08DG4	NRND	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	VN08	
SN75HVD08DR	NRND	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	VN08	
SN75HVD08P	ACTIVE	PDIP	Р	8	50	RoHS & Green	NIPDAU	N / A for Pkg Type	0 to 70	75HVD08	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

⁽⁵⁾ Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.



PACKAGE OPTION ADDENDUM

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(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN65HVD08DR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
SN75HVD08DR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1

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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN65HVD08DR	SOIC	D	8	2500	356.0	356.0	35.0
SN75HVD08DR	SOIC	D	8	2500	340.5	336.1	25.0

PACKAGE MATERIALS INFORMATION

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TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
SN65HVD08D	D	SOIC	8	75	507	8	3940	4.32
SN65HVD08DG4	D	SOIC	8	75	507	8	3940	4.32
SN65HVD08P	Р	PDIP	8	50	506	13.97	11230	4.32
SN75HVD08D	D	SOIC	8	75	507	8	3940	4.32
SN75HVD08DG4	D	SOIC	8	75	507	8	3940	4.32
SN75HVD08P	Р	PDIP	8	50	506	13.97	11230	4.32



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES:

- 1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
- 4. This dimension does not include interlead flash.
- 5. Reference JEDEC registration MS-012, variation AA.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



P (R-PDIP-T8)

PLASTIC DUAL-IN-LINE PACKAGE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MS-001 variation BA.



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